

Generic Copy

Issue Date: 03-May-2013

TITLE: Lead frame change SOIC 20 and SOIC 28 from UTAC

PROPOSED FIRST SHIP DATE: 03-Aug-2013

AFFECTED CHANGE CATEGORY(S): Bill of Materials

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or Charlie Yu < charlie.yu@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Office

ADDITIONAL RELIABILITY DATA: Available

Contact your local ON Semiconductor Sales Office or Francis Lualhati< ffxczy@onsemi.com >

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

L/F supplier change due to the floods in Thailand in 2011.

The change in L/F results in a change in MSL level. The new L/F has an MSL 3 rating.

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RELIABILITY DATA SUMMARY SOIC 28:

RELIABILITY TEST	CONDITION	SIS	ONSQF0099.1	ONSQF0100.1	ONSQF0101.1	ONSQF0102.1
1. PRECON LEVEL 3			CONTROL LOT	QUAL LOT-1	QUAL LOT-2	QUAL LOT-3
- ELECTRICAL TEST		153 UNITS/LOT	0/153	0/153	0/153	0/153
- VISUAL INSPECTION	40X		0/153	0/153	0/153	0/153
- TMCL 5 CYC	-65/150C					
- BAKE 24 HRS	125C					
- SOAK L3 192 HRS	30C/60%RH					
- CONVECTION REFLOW 3X	260C(+0-5'C)					
- FLUX IMMERSE	, ,					
- VISUAL INSPECTION	40X		0/153	0/153	0/153	0/153
- ELECTRICAL TEST						
			1/153 BIN4 =1	2/153 BIN4 = 2	2/153 BIN4 = 2	0/153
- FA NON-DESTRUCTIVE ANALYSIS			BIN4=1FUNC;VRSET	BIN4=2 FUNC;VRSET	BIN4=2FUNC;VRSET	51100
- RETEST WITH NEW PROGRAM			PASS =1	PASS=2	PASS=2	
2.ACLV_P_L3		(74	72	72	76
2.1 96 HRS.	121°C/100%RH		14	12) 	10
- ELECTRICAL TEST	1210110071111	<u> </u>				
- ELECTRICAL TEST			0/74	0/72	0/72	0/76
3.TMCL-P_L3			77	77	77	77
3.1 100 CYCS.	-65/150C	77 /LOT	"	· "	· "	"
- ELECTRICAL TEST	-6371300	77701				
- ELECTRICAL TEST			0177	0177	0177	0177
		<u> </u>	0/77	0/77	0177	0/77
3.2 500 CYCS.	-65/150C					
- ELECTRICAL TEST						
			0177	0/77	0/77	0/77
4. DPA		5UNITS/LOT				
4.1 POST TMCL-P_L3 @ 500 CYC			NOV03-21,12	NOV03-21,12	NOV03-21,12	NOV03-21,12
			0/5	0/5	0/5	0/5
				-	-	
5 . HTS V/O PRECON			80	80	80	80
5.1 168 HRS	150C	80 /LOT				
- ELECTRICAL TEST						
			1/80	1/80	0480	0480
- FA NON-DESTRUCTIVE ANALYSIS			BIN5;CC/CSS_PINTEST	BIN4;VRSET		
- RETEST VITH NEV PROGRAM			PASS =1	PASS =1		
5.2 504 HRS	150C	80 /LOT				
- ELECTRICAL TEST						
			0180	0/80	0/80	0480
5.3 1000 HRS	150C	80 /LOT				
- ELECTRICAL TEST						
			0480	0480	0480	0480

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RELIABILITY DATA SUMMARY SOIC 28 Continued:

6. MSL TEST-L3 (@ 260C		10 UNITS / LOT				
- ELECTRICAL TE	ST			0/10	0/10	0/10	0/10
- VISUAL INSPECT	TION	40X		0/10	0/10	0/10	0/10
- C+TSAM PRE-S	TRESS						
DIE				0/10	0/10	0/10	0/10
DAP				0/10	0/10	0/10	0/10
LEAD				0/10	0/10	0/10	0/10
TSAM				0/10	0/10	0/10	0/10
- BAKE	24 HRS	125C					
- SOAK L3	192 HRS	30C/60%RH					
- CONVECTION RE	EFLOW 3X	260C(+0-5'C)					
- VISUAL INSPECT	ION	40X		0/10	0/10	0/10	0/10
- ELECTRICAL TES	ST .						
				0710	0/10	0/10	0/10
- C+TSAM POST-S	STRESS						
DIE				0710	0/10	0/10	0/10
DAP				0/10	0/10	0/10	0/10
LEAD				0/10	0/10	0/10	0/10
TSAM			<u> </u>	0/10	0/10	0/10	0/10
- X-SECTION		100X	2 UNITS/ LOT	0/2	0/2	0/2	0/2
- DECAPSULATIO	ON		2 UNITS/ LOT	0/2	0/2	0/2	0/2

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RELIABILITY DATA SUMMARY SOIC 20:

DELIADILITY TEST	COMPITION	CAMPLE	ONSQF0071.1	ONSQF0072.1	ONCOE0072.1	CTATUC
RELIABILITY TEST	CONDITION	SAMPLE	UNSQF0071.1	UNSQF0072.1	ONSQF0073.1	STATUS
1. PRECON LEVEL 3 @ 260C		160/LOT				
- ELECTRICAL TEST			0/160	0/160	0/160	DONE
- TMCL 5 CYC	-65/150C					DONE
- BAKE 24 HRS	125C					DONE
- SOAK L3 192 HRS	30.C\60%BH					DONE
- CONVECTION REFLOW 3X	260'C (+0/-5'C)					DONE
- FLUX IMMERSE						DONE
- EXTERNAL VISUAL INSPECTION	40X					DONE
			0/160	0/160	0/160	DONE
- ELECTRICAL TEST						DONE
			07160	0/160	2/160 B4,FUNC=2	DONE
- CUSTOMER CONSIDER					FUNC ;INVALID UNIT=2	
- 1st RETEST					2/2 OUT_LEAK_VBATT	DONE
- 2nd RETEST					0/2	DONE,OCT30,12
2. ACLY-P_L3						
2.1 96 HRS	121C/15PSIG/100%RH	80/LOT				DONE
- ELECTRICAL TEST						DONE
			0/80	0/80	0480	
3.TMCL-P_L3			80	80	80	
3.1 200 CYCS	-65/150C	80/ LOT				DONE
- ELECTRICAL TEST						DONE
			0/80	0180	0/80	
3.2 500 CYCS	-65/150C	80/ LOT				DONE
- ELECTRICAL TEST	5311535					DONE
ELECTRICITE TECT			0/80	1/80 BIN6=1	0480	55/42
- RETEST			0100	SHORT PIN12=1	0.00	DONE NOV01-02,12
- HETEST						DONE 100 V01-02,12
- FA NON-DESTRUCTIVE				NOT FOUND ASSEMBLY RELATED		DONE NOV14,12
4. DPA TEST		5 /LOT	5	5	5	
4.1 POST TMCL-P @ 500 CYC						DONE
			0/5	0/5	0/5	DONE
5 . HTS WO PRECON			80	80	80	
5.1 168 HRS	150C	80 /LOT				DONE
- ELECTRICAL TEST						DONE
			0480	0/80	0/80	
5.2 504 HRS	150C	80 /LOT				DONE
- ELECTRICAL TEST						DONE
			0480	0/80	3/80 B4-PARA;ILEAK =2	
					B6; FUNCTION =1	
- 1st RETEST					3/3 OUT_LEAK_VBATT	DONE
- 2nd RETEST					0/3	DONE,OCT30,12
5.3 1000 HRS	150C	80 /LOT				DONE
- ELECTRICAL TEST						DONE
			1/80	0/80	4/80	
			VBATT_21V_		ORT OUTS_PIN12 AT PIN1	2 = 2
			OUT8			
EA NON DECTRUCTURE			AKAOF BU		ATT_21V_OUT8 AT PIN12	= 2
- FA NON-DESTRUCTIVE		LE	AKAGE PIN 12	=1	LEAKAGE PIN 12 = 4	
- RETEST			SHORT=1		SHORT = 3 ,BIN6=1	
- FA NON-DESTRUCTIVE			NOT FOUND ASSEMBLY		NOT FOUND ASSEMBLY RELATED	DONE
1000 HRS (RETEST GOOD @ 504 Hrs			DELITED		3	
- ELECTRICAL TEST						DONE
					0/3	
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RELIABILITY DATA SUMMARY SOIC 20 Continued:

6. MSL-L3		107 LOT	10	10	10	
- C-SAM PRE-STRESS			SEP11,12	SEP11,12	SEP11,12	DONE
DIE			0/10	0/10	0/10	
DAP			0/10	0/10	0/10	
LEAD			0/10	0/10	0/10	
TSAM			0/10	0/10	0/10	
- BAKE 24 HRS	125C					DONE
- SOAK L3 192 HRS	30.C\ 60%BH					DONE
- CONVECTION REFLOW 3X	260°C (+0/-5°C)					DONE
- EXTERNAL VISUAL INSPECTION	40X		0/10	0/10	0/10	DONE
- C-SAM POST-STRESS						DONE
DIE			0/10	0/10	0/10	
DAP			0/10	0/10	0/10	
LEAD			0/10	0/10	0/10	
TSAM			0/10	0/10	0/10	
- ELECTRICAL TEST						DONE
			0/10	0/10	0/10	DONE

CHANGED PART IDENTIFICATION: None

List of affected General Parts:

CAT4026V-T1 SOIC 28 CAT310W-T1 SOIC 20

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